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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/722,319	11/24/2003	Hong-Gun Kim	5649-1182	9100	
20792	7590 05/03/2005		EXAM	EXAMINER	
MYERS BIGEL SIBLEY & SAJOVEC			GOUDREAU, GEORGE A		
PO BOX 37428 RALEIGH, NC 27627			ART UNIT	PAPER NUMBER	
			1763		

DATE MAILED: 05/03/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)			
	10/722,319	KIM ET AL.			
Office Action Summary	Examiner	Art Unit			
	George A. Goudreau	1763			
The MAILING DATE of this communication Period for Reply	appears on the cover sheet with	the correspondence address			
A SHORTENED STATUTORY PERIOD FOR RETHE MAILING DATE OF THIS COMMUNICATION - Extensions of time may be available under the provisions of 37 CF after SIX (6) MONTHS from the mailing date of this communication - If the period for reply specified above is less than thirty (30) days, - If NO period for reply is specified above, the maximum statutory provided to the period for reply within the set or extended period for reply will, by some any reply received by the Office later than three months after the rearned patent term adjustment. See 37 CFR 1.704(b).	ON. R 1.136(a). In no event, however, may a replace. a reply within the statutory minimum of thirty eriod will apply and will expire SIX (6) MONTI tatute, cause the application to become ABA	ly be timely filed (30) days will be considered timely. 1S from the mailing date of this communication NDONED (35 U.S.C. § 133).	n.		
Status					
1) Responsive to communication(s) filed on 6	06 January 2005.				
2a) ☐ This action is FINAL . 2b) ☑	This action is non-final.				
Since this application is in condition for allowance except for formal matters, prosecution as to the merits is					
closed in accordance with the practice und	ler Ex parte Quayle, 1935 C.D.	11, 453 O.G. 213.			
Disposition of Claims					
4) ☐ Claim(s) 1-6,8-15,17-21,31-36,38 and 39 in 4a) Of the above claim(s) is/are with 5) ☐ Claim(s) 15,17,19-21,31, 33-36, and 38-38 6) ☐ Claim(s) 1-6,8-14,18 and 32 is/are rejected 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction as	ndrawn from consideration. g is/are allowed. d.				
Application Papers					
9)☐ The specification is objected to by the Exar	miner.				
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.					
Applicant may not request that any objection to		·			
Replacement drawing sheet(s) including the co	• • • • • • • • • • • • • • • • • • • •	•	d).		
Priority under 35 U.S.C. § 119					
12) Acknowledgment is made of a claim for for a) All b) Some * c) None of: 1. Certified copies of the priority docun 2. Certified copies of the priority docun 3. Copies of the certified copies of the application from the International Bu * See the attached detailed Office action for a	nents have been received. nents have been received in Ap priority documents have been r rreau (PCT Rule 17.2(a)).	plication No eceived in this National Stage	oudreau		
Attachment(s)		PRIMARY EXAMINI	ER		
1) Notice of References Cited (PTO-892)		mmary (PTO-413)			
 Notice of Draftsperson's Patent Drawing Review (PTO-948 Information Disclosure Statement(s) (PTO-1449 or PTO/St Paper No(s)/Mail Date 	· —	Mail Date ormal Patent Application (PTO-152) -			

Art Unit: 1763

1. Applicant's arguments with respect to claims of record have been considered but are most in view of the new ground(s) of rejection.

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

3. Claims 1, 3-6, and 10-11 are rejected under 35 U.S.C. 102(b) as being anticipated by Yamashita et. al. (JP 04-234,148).

Yamashita et. al. disclose a process for fabricating a device which is comprised of the following steps:

- -A patterned Al wiring layer (3) is formed onto the surface of a gate oxide layer (2) on a Si wafer (1).;
- -A PSG ILD (4) is conformably formed onto the surface of the wafer.;
- -A SOG layer (5) is conformably formed onto the surface of the PSG ILD (4).;
- -The SOG layer is baked at 125 C.;
- -The baked SOG layer is etched back using a rie etching process.;
- -The SOG layer is baked at 250 C.;
- -The SOG layer is baked at 400 C.; and
- -A PSG layer (6) is conformably formed onto the surface of the SOG layer (5).

This is discussed specifically in the abstract; and discussed in general in columns 1-12. This is shown in figures 1-13.

Art Unit: 1763

4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Page 3

- 5. This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).
- 6. Claims 2, 8-9, and 12-13 are rejected under 35 U.S.C. 103(a) as being unpatentable over the reference as applied in paragraph 3 above.
 - The reference as applied in paragraph 3 above fail to disclose the following aspects of applicant's claimed invention:
 - -the specific cmp planarization of the top psg film after it has been formed onto the wafer in the process taught above;
 - -the specific means for forming the SOG film in the process taught above which are claimed by the applicant;
 - -the specific usage of an aqueous HF solution to etch back the SOG film in the process taught above; and

Art Unit: 1763

-the specific usage of a CVD process to form the psg film in the process taught above

It would have been obvious to one skilled in the art to cmp planarize the psg film which is formed in the process taught above based upon the following. It would have been desirable to flatten the psg film in the process taught above in order to facilitate the formation of a subsequently formed wiring layer, which is both flat, and level. This would desirably facilitate the vertical stacking of additional layers of circuitry on the wafer. Additionally, it would have been desirable to form subsequently formed layers of circuitry which are flat, and level since this type of circuitry would be less subject to delaminating during any subsequent thermal processing (i.e.-wave soldering of components, annealing, etc.) than other shapes of circuitry would be.

It would have been obvious to one skilled in the art to form the SOG layer in the process taught above using the specific means, which are taught by the applicant based upon the following. The usage of the specific means, which are claimed by the applicant for forming an SOG layer on the surface of a wafer, is conventional or at least well known in the semiconductor processing arts. (The examiner takes official notice in this regard.) Further, this would have simply represented the usage of an alternative, and at least equivalent means for forming an SOG layer on the surface of a wafer to the specific usage of other such means for do such.

It would have been obvious to one skilled in the art to form the PSG layer in the process taught above using the specific means, which are claimed by the applicant based upon the following. The usage of a CVD process to form a PSG film on the

Art Unit: 1763

surface of a wafer is conventional or at least well known in the semiconductor processing arts. (The examiner takes official notice in this regard.) Further, this simply represents the usage of an alternative, and at least equivalent means for forming the PSG layer in the process taught above to the specific usage of other such means for doing such.

It would have been obvious to one skilled in the art to use an aqueous HF solution to etch back the SOG layer in the process taught above based upon the following. The usage of an aqueous HF solution to wet etch a SOG layer is conventional or at least well known in the semiconductor processing arts. (The examiner takes official notice in this regard.) Further, this simply represents an alternative, and at least equivalent means for etching back the SOG layer in the process taught above to the specific means, which are taught above.

7. Claims 1-6, 8-14, 18, and 32 are rejected under 35 U.S.C. 103(a) as being unpatentable over the reference as applied in paragraph 5 of the previous office action further in view of Yamashita et. al. (JP 04-234,148).

The reference as applied in paragraph 5 of the previous office action fail to specifically disclose the specific SOG baking temperatures, which are claimed by the applicant.

Yamashita et. al. teach that it is desirable to soft bake an SOG which has deposited onto the surface of a wafer at an initial temperature of 125 C.

Art Unit: 1763

It would have been obvious to one skilled in the art to soft bake the SOG layer in the process taught above at 125 C based upon the teachings of Yamashita et. al. that it is desirable to do such.

Page 6

- 8. Claims 15, 17, 19-21, 31, 33-36, and 38-39 are allowed.
- 9. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.
- 10. This action will not be made final due to the new grounds of rejection.

Joudreau

11. Any inquiry concerning this communication should be directed to examiner George A. Goudreau at telephone number (571)-272-1434.

Primary Examiner

Art Unit 1763